

Search Notes

Application/Control No.

10/523,992

Examiner

David E. Bochna

Applicant(s)/Patent under
Reexamination

JEONG, CHANG LOG

Art Unit

3679

SEARCHED

Class	Subclass	Date	Examiner
285	319	8/25/2006	DB
	307		
	317		
	321		
	340		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner